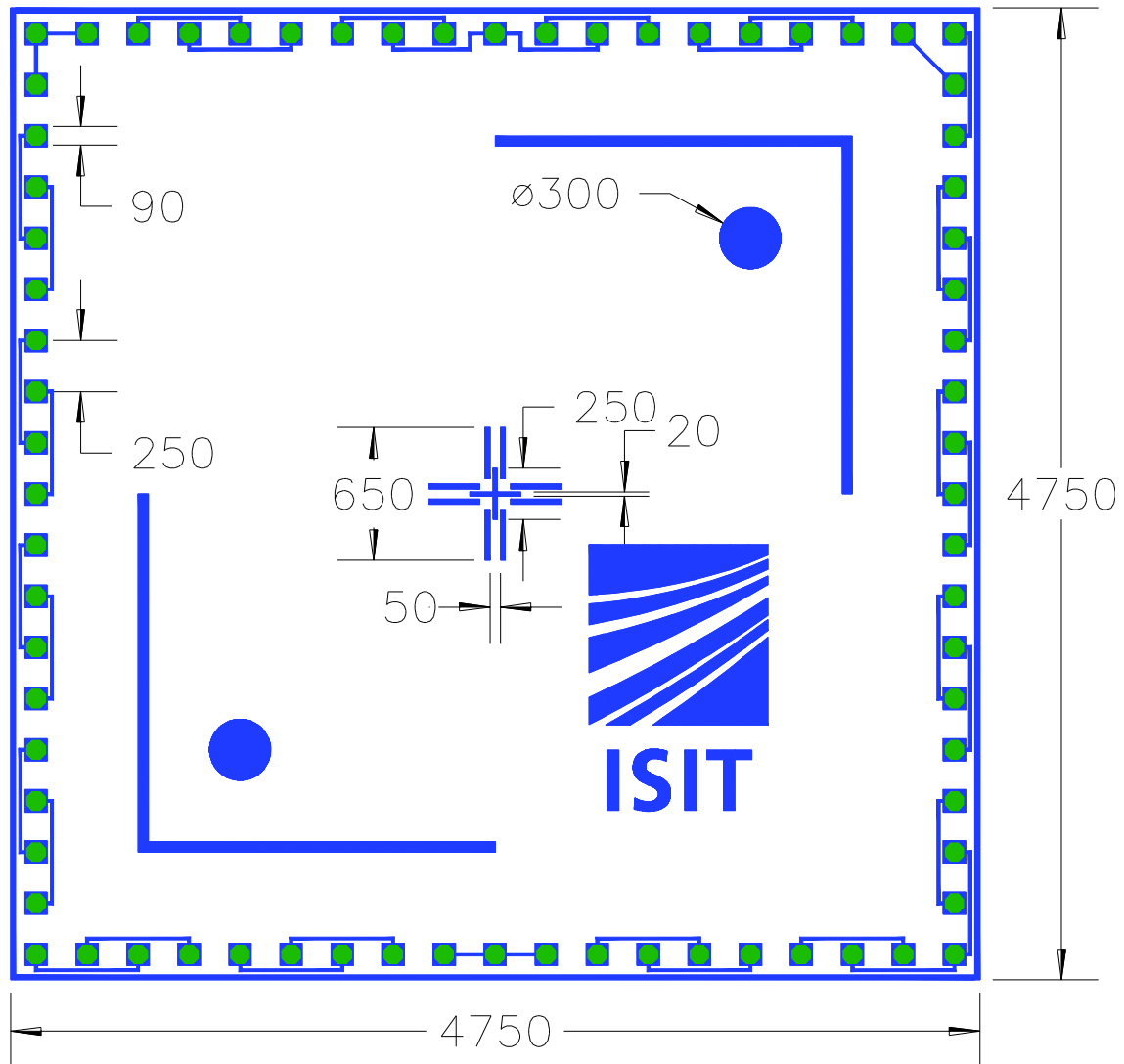

	PRODUCT DATA SHEET	page: 1 of 2
	Silicon Test Wafer FC475 DDC 8"	last update 20.02.2017

**LAYOUT:**



**TECHNICAL DATA:**

- Flip Chip Silicon Die
- dummy component with two nested daisy chains, allowing
  - easy measurement of short cuts between adjacent contacts
  - advanced reliability tests with voltage applied between adjacent pads
- 4 Kelvin sensing structures for 4-point probe contact resistance measurement
- fiducial marks for automated placement
- design size 4.75 mm x 4.75 mm with 100 µm dicing street
- aluminium pads 110 µm x 110 µm
- octagonal opening passivation 90 µm
- contact pitch 250 µm
- custom specific wafer thickness
- pad modifications with electroless NiAu, stud bumping and solder available

	PRODUCT DATA SHEET	page: 2 of 2
	<b>Silicon Test Wafer FC475 DDC 8"</b>	last update 20.02.2017

**TECHNICAL INFORMATION:**

<b>designed chip size</b>	4.75 mm x 4.75 mm
<b>die pitch</b>	4.85 mm x 4.85 mm
<b>typical die size after dicing</b>	4.80 mm x 4.80 mm
	other geometries, e.g. 4x4 dies available on request
<b>wafer thickness</b>	725µm, other thicknesses available on request
<b>pad layout</b>	72 pads, two nested daisy chains with 250µm pitch and 4 Kelvin sensing structures for contact resistance measurement
<b>pad geometry</b>	aluminum: 110µm x 110µm (square) passivation opening: 90µm x 90µm (octagonal)
<b>pad metal</b>	1.4 µm AlCu0.5
<b>passivation</b>	PECVD: 300 nm LTO + 800 nm SiN
<b>optional pad modifications</b>	solder bumps, stud bumps, electroless NiAu
<b>delivery</b>	8" wafer, 1100 dies FC475DDC + 6 dies FC475, diced on tape
<b>normal uses</b>	High throughput die and flip chip placing from wafer feeder, automatic wire bonding, encapsulation and underfill processes. Reliability tests with voltage applied between adjacent pads.
<b>typical technologies</b>	<ul style="list-style-type: none"> <li>• wire bonding</li> <li>• stud-bump bonding</li> <li>• solder flip chip</li> <li>• anisotropic conductive adhesive flip chip (ACA / ESC5)</li> <li>• isotropic conductive adhesive flip chip (ICA)</li> </ul>
<b>available substrates</b>	Substrates may be designed on request
<b>contact</b>	<p>Fraunhofer Institut Siliziumtechnologie  Fraunhoferstraße 1; D-25524 Itzehoe  Internet: <a href="http://www.isit.fraunhofer.de">http://www.isit.fraunhofer.de</a></p> <p>Dr.-Ing. Dipl. Phys. Dirk Kähler  Phone +49 (0) 48 21 / 17 – 46 04  Fax +49 (0) 48 21 / 17 – 42 50  Email: <a href="mailto:dirk.kaehler@isit.fraunhofer.de">dirk.kaehler@isit.fraunhofer.de</a></p> <p>Dr.-Ing. Wolfgang Reinert  Phone +49 (0) 48 21 / 17 – 42 16  Fax +49 (0) 48 21 / 17 – 42 50  Email: <a href="mailto:wolfgang.reinert@isit.fraunhofer.de">wolfgang.reinert@isit.fraunhofer.de</a></p>
<b>geometry variations</b>	Arbitrary customer-specific layouts including a company's logotype can be realised on 8" glass and silicon wafers.

\* Specifications subject to change without notice.